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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.		
09/386,646	08/31/1999	PIERRE C. FAZAN	660073.488D1	1639		
27076	7590 12/03/2003		EXAM	EXAMINER		
DORSEY & WHITNEY LLP			VU, HU	VU, HUNG K		
SUITE 3400	UAL PROPERTY DEPA	ART UNIT	PAPER NUMBER			
1420 FIFTH AVENUE			2811			
SEATTLE, W	VA 98101	DATE MAILED: 12/03/2003				

Please find below and/or attached an Office communication concerning this application or proceeding.

					X				
		Applicati	on No.	Applicant(s)					
Office Action Summary		09/386,6	46	FAZAN ET AL.					
		Examin	r	Art Unit					
		Hung K. \		2811					
	Th MAILING DATE of this communication app ars on the cover she it with the corresponding address Period for Reply								
THE I Exter after If the If NO Failu Any	ORTENED STATUTORY PERIOD FOR MAILING DATE OF THIS COMMUNIC, assions of time may be available under the provisions of SIX (6) MONTHS from the mailing date of this communicated period for reply specified above is less than thirty (30) of period for reply is specified above, the maximum statution reply within the set or extended period for reply set or extended period for reply set or extended period for reply within the set or extended period for reply within	ATION. 37 CFR 1.136(a). In no exication. days, a reply within the statory period will apply and w 1, by statute, cause the app	vent, however, may a re tutory minimum of thirty vill expire SIX (6) MONT plication to become ABA	ply be timely filed  (30) days will be considered timel  THS from the mailing date of this candoned (35 U.S.C. § 133).					
1)[🛛	Responsive to communication(s) filed	on <u>10 September</u>	<u>2003</u> .						
2a)□	This action is <b>FINAL</b> . 2b)		on-final.						
3)□	Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under <i>Ex parte Quayle</i> , 1935 C.D. 11, 453 O.G. 213.								
Disposition of Claims									
4)⊠	Claim(s) 44-68 is/are pending in the a	pplication.							
	4a) Of the above claim(s) is/are withdrawn from consideration.								
5)⊠	)⊠ Claim(s) <u>44 – 52 and 61 - 68</u> is/are allowed.								
6)⊠	S)⊠ Claim(s) <u>53,55-58 and 60</u> is/are rejected.								
7)⊠	☑ Claim(s) <u>54 and 59</u> is/are objected to.								
8) Claim(s) are subject to restriction and/or election requirement.									
Applicat	ion Papers								
9) The specification is objected to by the Examiner.									
10)□	10) The drawing(s) filed on is/are: a) accepted or b) objected to by the Examiner.								
	Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).								
_	Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).								
11) The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.									
Priority under 35 U.S.C. §§ 119 and 120									
a) 13)□ / s 3 a 14)□ /	Acknowledgment is made of a claim for a All b) Some * c) None of:  1. Certified copies of the priority do 2. Certified copies of the priority do 3. Copies of the certified copies of application from the International Acknowledgment is made of a claim for ince a specific reference was included in 7 CFR 1.78.  2) The translation of the foreign language acknowledgment is made of a claim for eference was included in the first senter	ocuments have been the priority documents have been the priority document Bureau (PCT Rufor a list of the cert domestic priority unin the first sentence uage provisional and domestic priority unin the first priority unit the first priority unin the first priority unit t	en received. en received in Appents have been alle 17.2(a)). tified copies not runder 35 U.S.C. (e of the specifical pplication has be under 35 U.S.C. (second context).	oplication No received in this National received. § 119(e) (to a provisiona ation or in an Application een received. §§ 120 and/or 121 since	al application) Data Sheet.				
Attachmen			_						
2) Notic	ce of References Cited (PTO-892) ce of Draftsperson's Patent Drawing Review (PTO mation Disclosure Statement(s) (PTO-1449) Pap			ummary (PTO-413) Paper No formal Patent Application (PT					

#### **DETAILED ACTION**

#### Request for Continued Examination

A request for continued examination (RCE) under 37 CFR 1.114, including the fee set forth in 37 CFR 1.17(e), was filed in this application after final rejection. Since this application is eligible for continued examination under 37 CFR 1.114, and the fee set forth in 37 CFR 1.17(e) has been timely paid, the finality of the previous Office action has been withdrawn pursuant to 37 CFR 1.114. Applicants' submission filed on 09/10/03 has been entered. An action on the RCE follows.

#### Claim Objections

2. Claim 1 is objected to because of the following informalities: In claim 1, line 6, "the first gate structure" should be changed to "the gate structure" for clarity. Appropriate correction is required.

#### Claim Rejections - 35 USC § 112

3. The following is a quotation of the second paragraph of 35 U.S.C. 112:

The specification shall conclude with one or more claims particularly pointing out and distinctly claiming the subject matter which the applicant regards as his invention.

Claims 55 and 60 are rejected under 35 U.S.C. 112, second paragraph, as being indefinite for failing to particularly point out and distinctly claim the subject matter which applicant regards as the invention.

In claims 55 and 60, lines 3-5, it is unclear as to what "a having second thickness" being Art Unit: 2811 referred to.

# Claim Rejections - 35 USC § 103

- The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all 4. obviousness rejections set forth in this Office action:
  - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are section 102 of this time, if the differences octave in the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

Claims 53 and 56 are rejected under 35 U.S.C. 103(a) as being unpatentable over Park et al. (PN 5,296,400, of record) in view of Poppert et al. (PN 4,593,459, of record).

Park et al. discloses, as shown in Figures 1F and 2H, a microelectronic device comprising:

- a microelectronic substrate (1);
- a gate oxide layer (4) formed on the substrate;
- a polysilicon gate layer (lower portion of 5) formed on the gate oxide layer;
- a field oxide (3) having a field oxide level between the level of an upper surface of the substrate and the level of an upper surface of the polysilicon gate layer.

Park et al. discloses the field oxide is a LOCOS. Park et al. does not disclose the field oxide is a trench isolation. However, Poppert et al. discloses a microelectronic device comprising a trench isolation (46,47). Note Figure 10 of Poppert et al.. Therefore, it would have been obvious to one of ordinary skill in the art at the time the invention was made to form the field oxide of Park et al. by trench isolation, such as taught by Poppert et al. in order to prevent the bird-beak effect and further isolate the devices from each others.

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With regard to claim 56, as shown in Figures 1F and 2H, Park et al. discloses a microelectronic device comprising:

a microelectronic substrate (1);

a gate oxide layer (4) formed on the substrate;

a polysilicon gate layer (lower portion of 5) formed on the gate oxide layer;

a field oxide (3) having a field oxide level between the level of an upper surface of the substrate and the level of an upper surface of the polysilicon gate layer;

a polysilicon adhesion layer formed over the polysilicon gate layer and the upper surface

Park et al. discloses the field oxide is a LOCOS. Park et al. does not disclose the field oxide is a of the field oxide. trench isolation. However, Poppert et al. discloses a microelectronic device comprising a trench isolation (46,47). Note Figure 10 of Poppert et al.. Therefore, it would have been obvious to one of ordinary skill in the art at the time the invention was made to form the field oxide of Park et al. by trench isolation, such as taught by Poppert et al. in order to prevent the bird-beak effect and further isolate the devices from each others.

Claims 57 and 58 are rejected under 35 U.S.C. 103(a) as being unpatentable over Park et al. (PN 5,296,400, of record) in view of Poppert et al. (PN 4,593,459, of record) and further in view of Lin et al. (PN 5,318,924, of record).

Park et al. and Poppert et al. discloses the invention substantially as claimed including the microelectronci device as recited in the rejection above. Park et al. and Poppert et al. do not disclose the device further comprising a silicide layer formed on the adhesion layer. However,

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Lin et al. discloses a silicide layer (32) formed on the adhesion layer (26). Note Figure 6 of Lin et al.. Therefore, it would have been obvious to one of ordinary skill in the art at the time the invention was made to form the device of Park et al. and Poppert et al. having a silicide layer on the adhesion layer, such as taught by Lin et al. in order to further reduce the contact resistance.

With regard to claim 58, Park et al., Poppert et al. and Lin et al. discloses the silicide comprising titanium silicide. Park et al., Poppert et al. and Lin et al. do not disclose the silicide layer comprises tungsten silicide. However, at Col. 4, lines 44-49, other refractory metals can be used in place of titanium. It is well-known that other refractory metals include tungsten. Therefore, it would have been obvious to one of ordinary skill in the art at the time the invention was made to substitute titanium with tungsten, since titanium and tungsten are both considered to be an art recognized functional equivalent as the refractory metal silicide material for semiconductor device.

# Allowable Subject Matter

- Claims 54 and 59 are objected to as being dependent upon a rejected base claim, but would be allowable if rewritten in independent form including all of the limitations of the base 6. claim and any intervening claims.
  - Claims 44 52 and 61 68 are allowed. 7.
  - The following is an examiner's statement of reasons for allowance: 8.

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Applicant's claims 44 - 52, 54, 59 and 61 - 68 are allowable over the references of record because none of these references disclose or can be combined to yield the claimed device comprising the second gate layer for the portion of the component structure formed on the isolation pad having a second height relative to the surface of the substrate surface les than the first height, as recited in claim 44, in combination with the remaining claimed limitations, the second gate layer for the portion of the component structure formed on the isolation pad having a second thickness greater than the first thickness, as recited in claim 49, in combination with the remaining claimed limitations, the polysilicon adhesion layer having an upper surface over the upper surface of the field oxide below the upper surface of the polysilicon adhesion layer over the polysilicon gate layer, as recited in claims 54 and 59, in combination with the remaining claimed limitations

### Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Hung K. Vu whose telephone number is (703) 308-4079. The 9. examiner can normally be reached on Mon-Thurs 6:00-3:30, alternate Friday 7:00-3:30, Eastern

If attempts to reach the examiner by telephone are unsuccessful, the examiner's Time. supervisor, Eddie C. Lee can be reached on (703) 308-1690. The Central Fax Number for the organization where this application or proceeding is assigned is (703) 872-9306.

Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the receptionist whose telephone number is (703) 308-0956.

Art Unit: 2811

Vu

November 24, 2003

Hunglh

Hung Vu

Patent Examiner